

PRESS RELEASE

FOR IMMEDIATE RELEASE

South Portland, USA & Yokohama, Japan

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Lasertec Corporation Announces the Purchase of a SICA88 by ON Semiconductor

Lasertec Corporation (Tokyo Stock Exchange: 6920) announced today that the Silicon Carbide Technology Division of ON Semiconductor (Nasdaq: ON), a world leading supplier of Wide Band Gap SiC discrete, modules, and drivers, has purchased a SICA88 SiC inspection and analysis tool manufactured by the Lasertec Corporation. This tool will be installed at the ON Semiconductor Silicon Carbide device manufacturing facility in South Portland, ME.

“For the past several years, Lasertec has been a leading equipment supplier for the SiC substrate and epitaxial industry and this purchase enables ON Semiconductor to gather data to further its already state-of-art SiC device technology. SICA88 provides advanced sensitivity, analysis capabilities, and high throughput that ON Semiconductor can utilize to improve the quality and reliability of our SiC devices. In addition, the SICA88 on-the-fly Automatic Defect Classification (ADC) with Deep Learning algorithm and high definition review images will improve yield performance and our bottom line.” commented Hrishikesh Das, Sr. Materials and Epitaxy Manager, Silicon Carbide Technology. “The SICA88’s photoluminescence and bright field combination will accurately detect and classify defects early on in the process flow and take corrective action, thus reducing the device failures downstream.” added Hrishikesh.

“The SICA inspection tool is designed to help fab engineers accelerate yield improvements by providing high sensitivity, high throughput defect inspection and highly accurate ADC along with a fully automated defect review feature. SICA enables SiC substrate and device manufactures to take corrective action sooner and improve their yield more quickly. The tool’s user interface provides an intuitive graphical method for creating inspection recipes, further increasing its ease of use for automated reporting. Lasertec will continue to pursue the development and advancement of defect inspection technologies in order to facilitate the further enhancement of power device quality and productivity,” said Hirokazu Seki, General Manager of Lasertec Technology Department1.

About Lasertec:

As a leader in metrology and inspection tooling, Lasertec Corporation has been serving the needs of semiconductor, compound semiconductor, renewable energy, FPD and other high technology industries for many years. Since its beginning in 1960, Lasertec has been evolving and growing to keep pace with the world’s rapidly expanding and changing high technology manufacturing requirements. In addition to the innovative technologies, Lasertec’s global support infrastructure assures customers full satisfaction through high tool availability that maximizes the capital investment and device yield. For more information, go to www.lasertec.co.jp/en

About ON Semiconductor:

ON Semiconductor (Nasdaq: [ON](#)) is driving energy efficient innovations, empowering customers to reduce global energy use. The company is a leading supplier of semiconductor-based solutions, offering a comprehensive portfolio of energy efficient, power management, analog, sensors, logic, timing, connectivity, discrete, SoC and custom devices. The company's products help engineers solve their unique design challenges in [automotive, communications, computing, consumer, industrial, medical, aerospace and defense applications](#). ON Semiconductor operates a responsive, reliable, world-class supply chain and quality program, a robust compliance and ethics program, and a network of manufacturing facilities, sales offices and design centers in key markets throughout North America, Europe and the Asia Pacific regions. For more information, visit <http://www.onsemi.com>.

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